

International Workshop on Radiation Imaging Detectors iWoRID 2011

Tuesday, July 5, 2011

Poster Mini Talks VI - HG E7 (3:15 PM - 3:40 PM)

-Conveners: Seppo Nenonen

time	[id] title	presenter
3:15 PM	[175] Laboratory X-ray microscopy with a nano-focus X-ray source	Mr NACHTRAB, Frank
3:16 PM	[211] 3D particle distribution in Water Phantom in Therapy Beam	OPALKA, Lukas
3:17 PM	[93] Application of a pnCCD in protein crystallography	SEND, Sebastian
3:18 PM	[216] Improving the spatial resolution of a soft X-ray Charge Coupled Device (CCD) used for Resonant Inelastic X-ray Scattering	Mr MATTHEW, Soman
3:19 PM	[112] Detective quantum efficiency of photon-counting detectors having edge-on geometry under mammography imaging condition	Mr YUN, Seungman
3:20 PM	[222] Integrated USB based readout interface for silicon strip detectors of the ATLAS SCT module	Mr MASEK, Petr
3:21 PM	[157] Measurement of secondary radiation with the pixel detector Timepix during ion beam therapy	Dr MARTISIKOVA, Maria
3:22 PM	[232] Micro-tomographic study of metal grainy structure	VAVRIK, Daniel
3:23 PM	[180] Mobile system for in-situ imaging of cultural objects	Mr ZEMLICKA, Jan
3:24 PM	[174] Performance evaluation of a PET demonstrator for PET-MR imaging based on monolithic LYSO:Ce scintillators	SARASOLA, Icíar
3:25 PM	[106] A Range Verification Method for Proton Therapy using a Photon Counting Detector	Prof. KIM, Jin Sung
3:26 PM	[88] Monte Carlo simulations on performance of double-scattering Compton camera	Mr PARK, Jin Hyung
3:27 PM	[156] Preliminary Study on Neutron image using new crystal scintillator	Dr KIM, Hyunduk
3:28 PM	[185] Semiconductor pixel detector with absorption grid as a tool for charge sharing studies and energy resolution improvement	Mr KREJCI, Frantisek
3:29 PM	[217] Smart dosimetry by pattern recognition using a single photon counting detector system in time over threshold mode	Mr REZA, Salim
3:30 PM	[184] Use of the Medipix2 Based CdTe Microprobe in Dental Imaging	Mr VYKYDAL, Zdenek
3:34 PM	[131] "Double-layer" Method to Improve Image Quality of Industrial SPECT	Prof. KIM, Chan Hyoeng